

Notice of References Cited	Application/Control No. 10/002,176	Applicant(s)/Patent Under Reexamination YANG ET AL.	
	Examiner Vikki H Trinh	Art Unit 2814	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,010,940	01-2000	Lee et al.	438/396
	B	US-			
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	K	US-			
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	M	US-			

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NON-PATENT DOCUMENTS

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